

Docket No. 292759US0PCT



MAIL STOP PCT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Frederic MAZEN, et al.

SERIAL NO: 10/584,053

GAU:

FILED: June 22, 2006

EXAMINER:

FOR: METHOD FOR THE ORGANISED GROWTH OF NANOSTRUCTURES

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references cited in the International Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

Norman F. Oblon

Registration No. 24,618

Customer Number

22850

Tel. (703) 413-3000
Fax. (703) 413-2220
(OSMMN 05/03)

Surinder Sachar

Registration No. 34,423

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

292759US0PCT

SERIAL NO.

10/584,053

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Frederic MAZEN, et al.

FILING DATE

June 22, 2006

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5 935 454	08/10/1999	TADA et al.			
	AB	4 908 226	03/13/1990	KUBENA et al.			
	AC	2003 0157744	08/21/2003	SCHLAF			
	AD	5 082 359	01/21/1992	KIRKPATRICK			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AT	KUBENA R. L. et al., "SELECTIVE AREA NUCLEATION FOR METAL CHEMICAL VAPOR DEPOSITION USING FOCUSED ION BEAMS", JOURNAL OF VACUUM SCIENCE AND TECHNOLOGY, Vol. B6 (6), pages 1865-1868, XP 000133336, 1988
	AU	GERLACH R., "FOCUSED ION BEAM METHODS OF NANOFABRICATION: ROOM AT THE BOTTOM", PROCEEDINGS OF SPIE, Vol. 4510, pages 96-106, XP 008035414, 2001
	AV	SCHMUKI P. et al., "SELECTIVE ELECTRODEPOSITION OF MICROPATTERNS ON PREDEFINED SURFACE DEFECTS ON P-Si (100)", JOURNAL OF ELECTROCHEMICAL SOCIETY, Vol. 148, pages 177-182, 2001
	AW	BARON T. et al., "SILICON QUANTUM DOT NUCLEATION ON Si ₃ N ₄ , SiO ₂ , AND SiO _x N _y SUBSTRATES FOR NANOELECTRONIC DEVICES", JOURNAL OF CRYSTAL GROWTH, Vol. 209, pages 1004-1008, 2000
	AX	BARON T. et al., "NUCLEATION CONTROL OF CVD GROWTH SILICON NANOCRYSTALS FOR QUANTUM DEVICES", MICROELECTRONIC ENGINEERING, Vol. 61-62, pages 511-515, 2002
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. PCT Application Serial No: 10/584,053

Filed: June 22, 2006

Frederic MAZEN, et al.

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STATEMENT OF RELEVANCY

- 1) References AA-AD & AT-AU have been cited in the International Search Report. A copy of these references is being submitted herewith.
- 2) References have been cited in the corresponding Search Report. A copy of these references is being submitted herewith.
- 3) References AV-AX are discussed in the specification. A copy of these references is being submitted herewith.
- 4) References are additional prior art known to Applicant. A copy of these references is being submitted herewith.